



**California Institute of Technology
Massachusetts Institute of Technology**

Document Change Notice (DCN)

DCN No. E080332-00

Sheet 1 of 1

DOCUMENT No. (DOC-REV-GP.ID)	TITLE	NEW REV
E060268-A-D	Specification Advanced LIGO Pathfinder	B

CHANGE DESCRIPTION (FROM/TO):

1.) Inspections: Add Highlighted Text

Scratches and Point defects methods 1 and 2	Visual Inspection	Hand sketch including scratch/pit dimensions
Scratches and Point defects method 3	Visual Inspection	Digital image of each inspection location

2.) Method 3, Change

From: An inspection is then carried out with a dark field microscope with a similar sampling frequency as described in section 2

To: An inspection is then carried out with a dark field microscope, with 5x objective at four positions at each of the following locations:

- a. Within 10mm of the center of the surface.
- b. Equally spaced along the circumference of a centered, 60 mm diameter circle.
- c. Equally spaced along the circumference of a centered, 120 mm diameter circle

REASON FOR CHANGE: Clarification

ACTION: Incorporate Change Attach DCN to Drawings Other Action (specify):

DISPOSITION OF HARDWARE (IDENTIFY SERIAL NUMBERS)	DCN DISTRIBUTION
<input type="checkbox"/> No hardware was affected (record change only):	LIGO/AdL management: excomm@ligo.caltech.edu AdL COC group: aligo_coc@ligo.caltech.edu QA & Safety: tyler_w@ligo.caltech.edu
<input type="checkbox"/> List S/Ns which comply already:	
<input type="checkbox"/> List S/Ns to be reworked/scrapped:	
<input checked="" type="checkbox"/> List S/N's to be built with this change: PF3	
<input type="checkbox"/> List S/Ns to be retested per this change:	
<input type="checkbox"/>	

SAFETY, COST, SCHEDULE, REQUIREMENTS IMPACT? NO YES (If YES, enter CR (CCB) or TCP (TRB) #)

APPROVALS:	DATE	OTHER APPROVALS (SPECIFY)	DATE
ORIGINATOR:	6-11-08		
TASK LEADER:			
GROUP LEADER:			
DCC RELEASE:			